ALPHA & OMEGA SEMICONDUCTOR

# AOB409L
60V P-Channel MOSFET

General Description

The AOB409L combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

Product Summary

V_{DS}	-60V
I_D (at V_{GS}=-10V)	-31.5A
$R_{DS(ON)}$ (at V_{GS}=-10V)	< 38mΩ
$R_{DS(ON)}$ (at V_{GS}=-4.5V)	< 50mΩ

100% UIS Tested
100% R_g Tested

Green Product
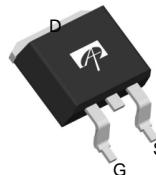
TO-263
D²PAK

Top View   Bottom View
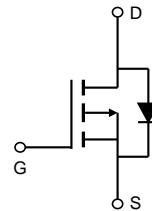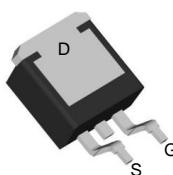
Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	-60	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current	T_C=25°C	I_D	-31.5	A
	T_C=100°C		-22	
Pulsed Drain Current [C]		I_{DM}	-85	
Continuous Drain Current	T_A=25°C	I_{DSM}	-5	A
	T_A=70°C		-4	
Avalanche Current [C]		I_{AS}, I_{AR}	37	A
Avalanche energy L=0.1mH [C]		E_{AS}, E_{AR}	68	mJ
Power Dissipation [B]	T_C=25°C	P_D	83.3	W
	T_C=100°C		41.6	
Power Dissipation [A]	T_A=25°C	P_{DSM}	2.1	W
	T_A=70°C		1.3	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{θJA}$	11	15	°C/W
Maximum Junction-to-Ambient [A D]	Steady-State		47	60	°C/W
Maximum Junction-to-Case	Steady-State	$R_{θJC}$	1.5	1.8	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Typ	Max	Units
STATIC PARAMETERS							
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=-250µA, V_{GS}=0V		-60			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=-60V, V_{GS}=0V				-1	µA
			T_J=55°C			-5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}=±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS}, I_D=-250µA		-1.2	-2.1	-2.4	V
$I_{D(ON)}$	On state drain current	V_{GS}=-10V, V_{DS}=-5V		-85			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=-10V, I_D=-20A			30	38	mΩ
			T_J=125°C		53	66	mΩ
		V_{GS}=-4.5V, I_D=-20A			39	50	mΩ
g_{FS}	Forward Transconductance	V_{DS}=-5V, I_D=-20A			32		S
V_{SD}	Diode Forward Voltage	I_S=-1A,V_{GS}=0V			-0.72	-1	V
I_S	Maximum Body-Diode Continuous Current [G]					60	A
DYNAMIC PARAMETERS							
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=-30V, f=1MHz		1969	2461	2953	pF
C_{oss}	Output Capacitance			125	178	231	pF
C_{rss}	Reverse Transfer Capacitance			72	120	168	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz			2	4	Ω
SWITCHING PARAMETERS							
Q_g(10V)	Total Gate Charge	V_{GS}=-10V, V_{DS}=-30V, I_D=-20A		34	43	52	nC
Q_g(4.5V)	Total Gate Charge			16	19.7	24	nC
Q_{gs}	Gate Source Charge			8	10.2	12	nC
Q_{gd}	Gate Drain Charge			5	8.9	12.5	nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=-10V, V_{DS}=-30V, R_L=1.5Ω, R_{GEN}=3Ω			12		ns
t_r	Turn-On Rise Time				14.5		ns
$t_{D(off)}$	Turn-Off DelayTime				38		ns
t_f	Turn-Off Fall Time				15		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=-20A, dl/dt=500A/µs		18	25.7	33	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=-20A, dl/dt=500A/µs		117	167	217	nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(MAX)}$=175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=175° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=175° C. The SOA curve provides a single pulse rating.

G. The maximum current limited by package.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Fig 1: On-Region Characteristics (Note E)
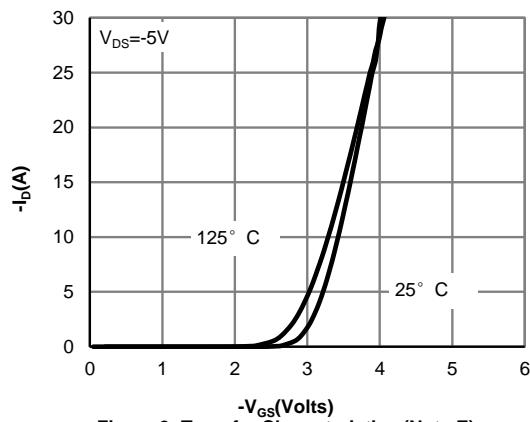
Figure 2: Transfer Characteristics (Note E)
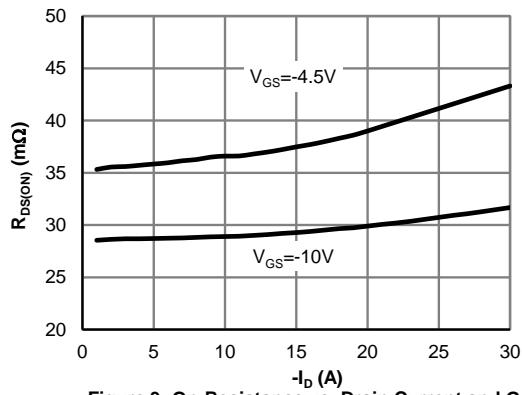
Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)
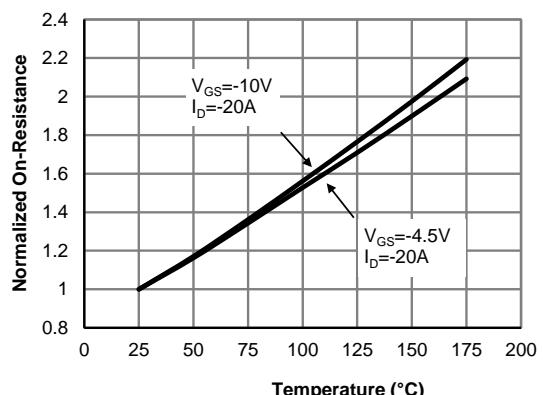
Figure 4: On-Resistance vs. Junction Temperature (Note E)
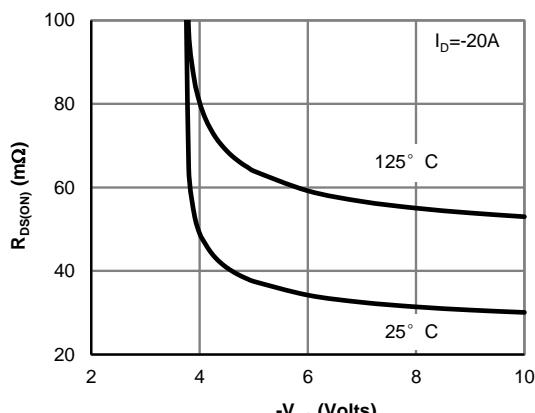
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)
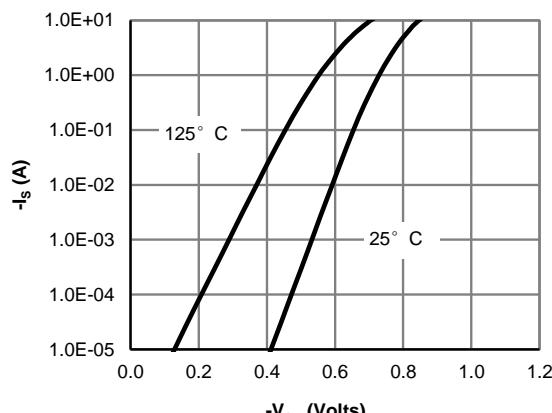
Figure 6: Body-Diode Characteristics (Note E)

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

V_{DS}=-30V
I_D=-20A
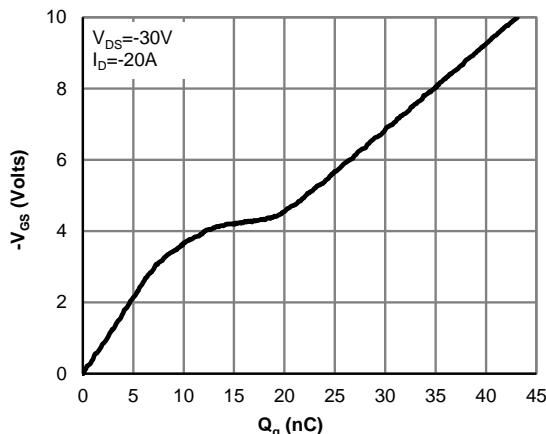
Figure 7: Gate-Charge Characteristics

C_{iss}

C_{oss}

C_{rss}
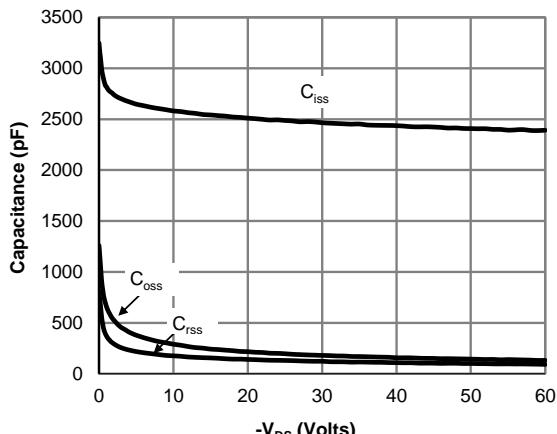
Figure 8: Capacitance Characteristics

$R_{DS(ON)}$ limited

10μs
100μs
1ms
10ms
DC

$T_{J(Max)}$=175°C
T_C=25°C
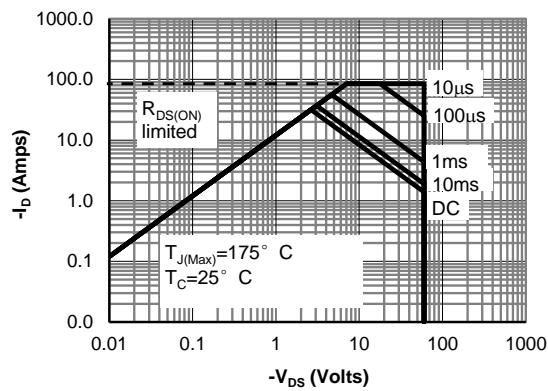
**Figure 9: Maximum Forward Biased
Safe Operating Area (Note F)**

$T_{J(Max)}$=175°C
T_C=25°C
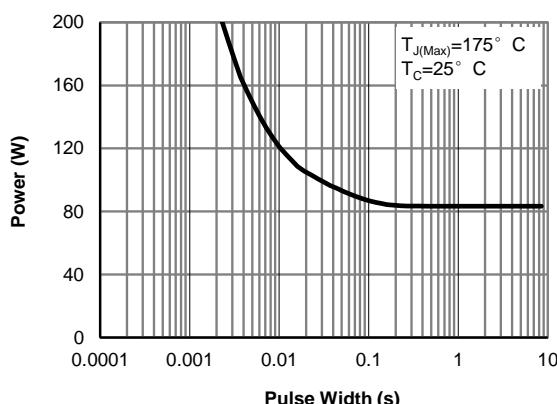
**Figure 10: Single Pulse Power Rating Junction-to-Case
(Note F)**

D=T_{on}/T
$T_{J,PK}$=T_C+P_{DM}·$Z_{\theta JC}$·$R_{\theta JC}$

$R_{\theta JC}$=1.8°C/W

In descending order
D=0.5, 0.3, 0.1, 0.05, 0.02, 0.01, single pulse

Single Pulse

P_n

T_{on}
T
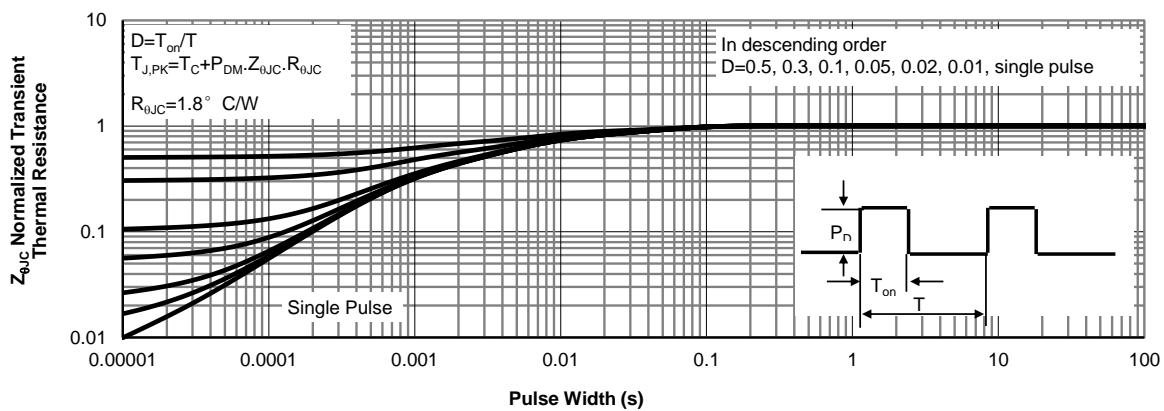
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS
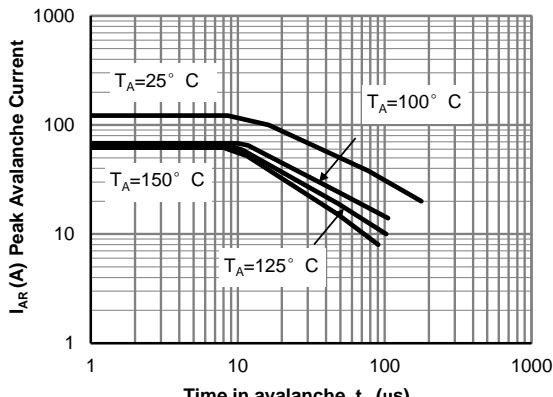


Figure 12: Single Pulse Avalanche capability (Note C)
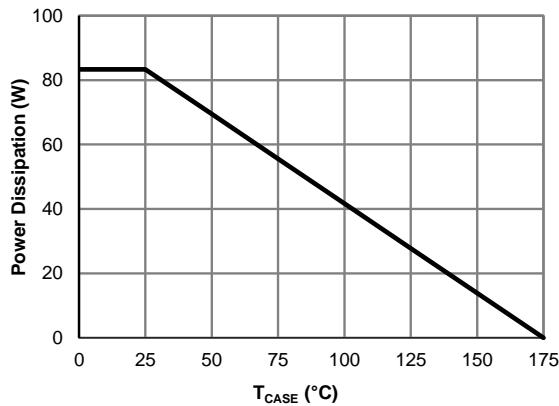

Figure 13: Power De-rating (Note F)
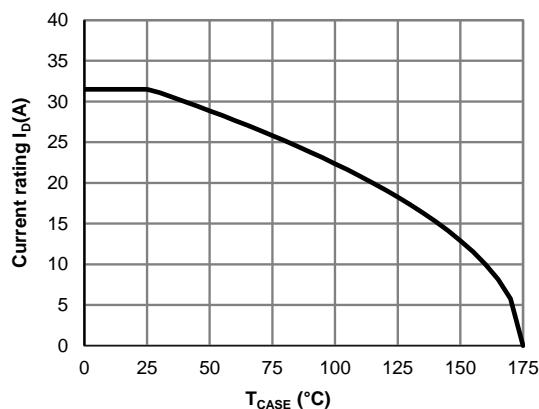

Figure 14: Current De-rating (Note F)
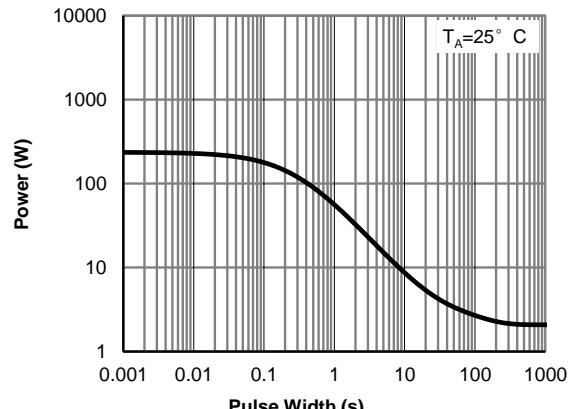
Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

$D=T_{on}/T$
$T_{J,PK}=T_A+P_{DM}\cdot Z_{\theta JA}\cdot R_{\theta JA}$
$R_{\theta JA}=60^\circ$ C/W

In descending order
D=0.5, 0.3, 0.1, 0.05, 0.02, 0.01, single pulse

Single Pulse
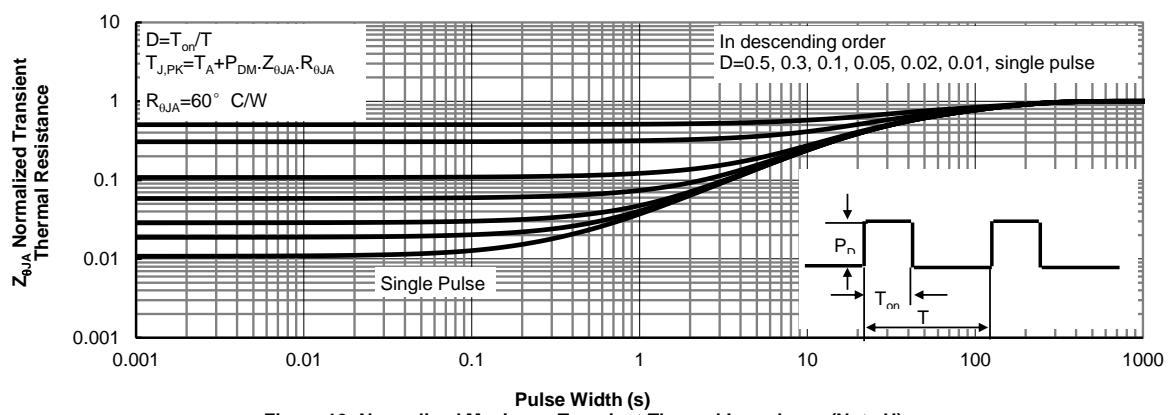
**Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)**

Gate Charge Test Circuit & Waveform
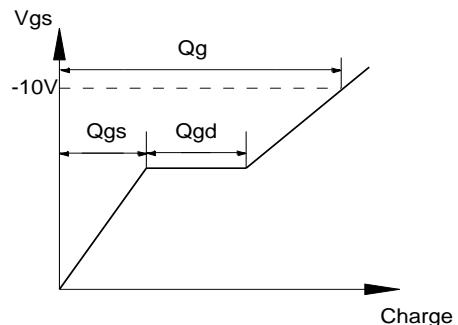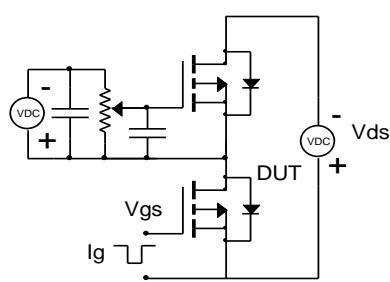
Resistive Switching Test Circuit & Waveforms
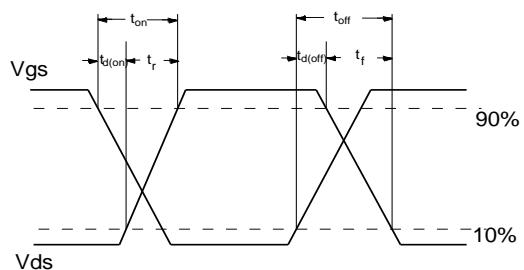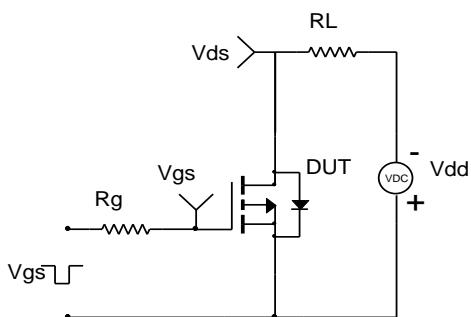
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

$$E_{AR} = 1/2 \ LI_{AR}^2$$
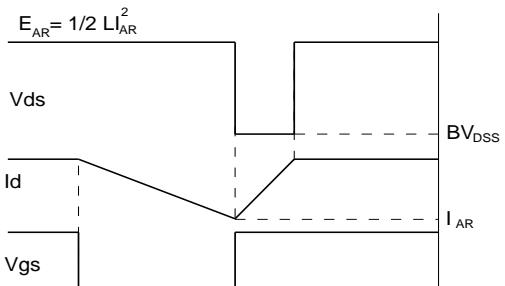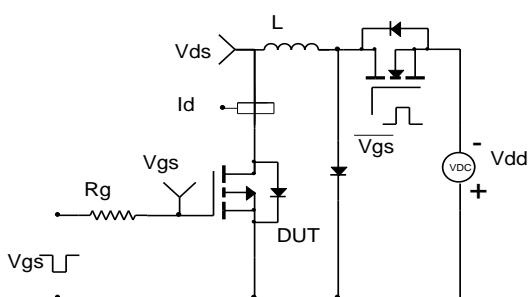
Diode Recovery Test Circuit & Waveforms

$$Q_{rr} = -\int Idt$$